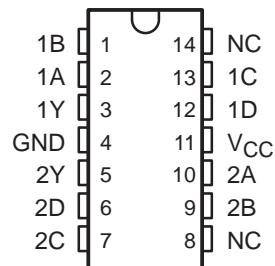


- Operation From Very Slow Edges
- Improved Line-Receiving Characteristics
- High Noise Immunity
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1- μ m Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs

D OR N PACKAGE
(TOP VIEW)



description

Each circuit functions as a 4-input NAND gate, but because of the Schmitt action, it has different input threshold levels for positive-going (V_{T+}) and negative-going (V_{T-}) signals.

The 74AC11013 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE

INPUTS				OUTPUT
A	B	C	D	Y
H	H	H	H	L
L	X	X	X	H
X	L	X	X	H
X	X	L	X	H
X	X	X	L	H

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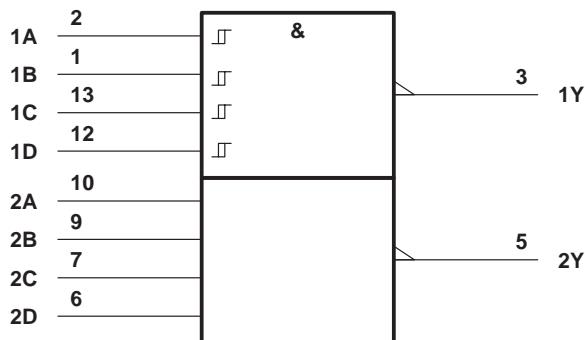
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74AC11013

DUAL 4-INPUT POSITIVE-NAND SCHMITT TRIGGER

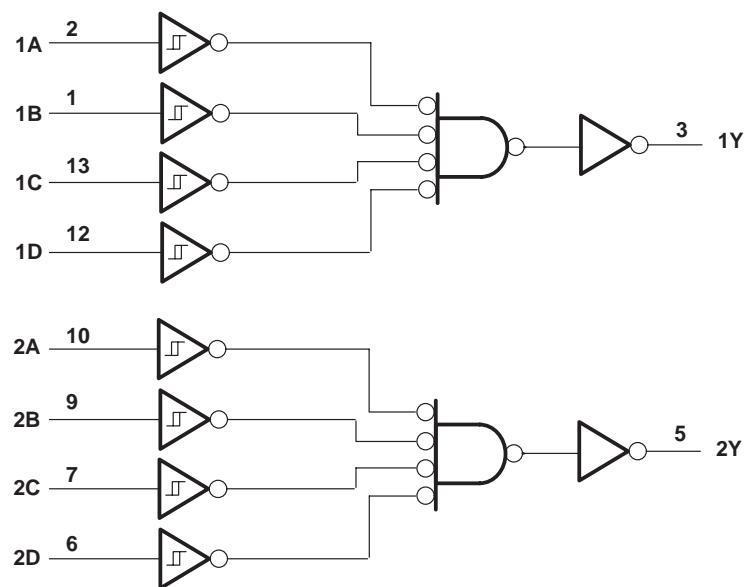
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input voltage range, V_I (see Note 1)	–0.5 V to V_{CC} + 0.5 V
Output voltage range, V_O (see Note 1)	–0.5 V to V_{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V_{CC} or GND pins	±100 mA
Storage temperature range	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

recommended operating conditions

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	3	5	5.5	V
V_{IH}	High-level input voltage	$V_{CC} = 3$ V	2.2		V
		$V_{CC} = 4.5$ V	3.2		
		$V_{CC} = 5.5$ V	3.9		
V_{IL}	Low-level input voltage	$V_{CC} = 3$ V	0.5		V
		$V_{CC} = 4.5$ V	0.9		
		$V_{CC} = 5.5$ V	1.1		
V_I	Input voltage	0	V_{CC}		V
V_O	Output voltage	0	V_{CC}		V
I_{OH}	High-level output current	$V_{CC} = 3$ V	–4		mA
		$V_{CC} = 4.5$ V	–24		
		$V_{CC} = 5.5$ V	–24		
I_{OL}	Low-level output current	$V_{CC} = 3$ V	12		mA
		$V_{CC} = 4.5$ V	24		
		$V_{CC} = 5.5$ V	24		
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	ns/V	
T_A	Operating free-air temperature	–40	85		°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	T _A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
V _{T+}		3 V		2.2	2.2			V
		4.5 V		3.2	3.2			
		5.5 V		3.9	3.9			
V _{T-}		3 V	0.5		0.5			V
		4.5 V	0.9		0.9			
		5.5 V	1.1		1.1			
V _{hys} (V _{T+} – V _{T-})		3 V	0.3	1.2	0.3	1.2		V
		4.5 V	0.4	1.4	0.4	1.4		
		5.5 V	0.5	1.6	0.5	1.6		
V _{OH}	I _{OH} = –50 µA	3 V	2.9		2.9			V
		4.5 V	4.4		4.4			
		5.5 V	5.4		5.4			
	I _{OH} = –4 mA	3 V	2.58		2.48			
		4.5 V	3.94		3.8			
	I _{OH} = –24 mA	5.5 V	4.94		4.8			
		5.5 V			3.85			
	I _{OL} = 50 µA	3 V		0.1	0.1			V
		4.5 V		0.1	0.1			
		5.5 V		0.1	0.1			
		3 V		0.36	0.44			
V _{OL}	I _{OL} = 12 mA	4.5 V		0.36	0.44			V
		5.5 V		0.36	0.44			
	I _{OL} = 24 mA	5.5 V		0.36	0.44			
		5.5 V			1.65			
I _I	V _I = V _{CC} or GND	5.5 V		±0.1	±1	µA		
I _{CC}	V _I = V _{CC} or GND, I _O = 0	5.5 V		4	40	µA		
C _i	V _I = V _{CC} or GND	5 V		3.5		pF		

† Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T _A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
t _{PLH}	A, B, C, D	Y	2.5	6.4	8.7	2.5	9.7	ns
			2.3	6.5	8.7	2.3	9.9	

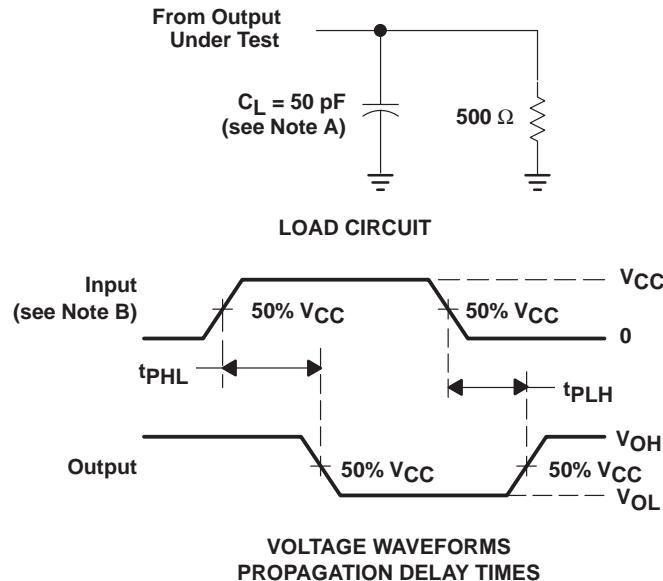
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T _A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
t _{PLH}	A, B, C, D	Y	2	4.2	6.4	2	7.1	ns
			2	4.4	6.9	2	7.8	

operating characteristics, $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C_{pd} Power dissipation capacitance	$C_L = 50$ pF, $f = 1$ MHz	29	pF

PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C_L includes probe and jig capacitance.
 B. Input pulses are supplied by generators having the following characteristics: $PRR \leq 10$ MHz, $Z_O = 50 \Omega$, $t_f = 3$ ns, $t_f = 3$ ns.
 C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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